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Form PTT 149 (Modified) I.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE				ATTY DOCKET NO.		SERIAL NO.			
(Modified) PATENT AND TRADEMARK OFFICE				285645US3PCT		10/567,034			
LIST OF REFERENCES CITED BY APPLICANT				APPLICANT					
				Naoki HASHIGUCHI					
				FILING DATE		GROUP			
				February 3, 2006					
U.S. PATENT DOCUMENTS									
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FOREIGN PATENT DOCUMENTS									
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES NO				
SK	AO	10-139327	05/26/98	JP ·		15,	<u> </u>	NO	
SK	AP	6-127868	05/10/94	JP				NO	
SK	AQ	1-69489	03/15/89	JP				NO	
SK	AR	1-145990	06/07/89	JP				NO	
SK	AS	124063/1975	10/11/75	JP				NO	
SK	AT	11-335039	12/07/99	JP				NO	
SK	AU	5-306083	11/19/93	JP (with English abstract)				NO	
SK	AV	9-165163	06/24/97	JP (with English abstract)				NO	
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)									
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Examiner /Stefan Kruer/					Date Considered 09/27/2006				
*Examiner: In	itial if re	eference is consider	ed, whether or not	citation is in conformance with MPFP 60	De: Draw lir	ne through			
*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.									